EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	279	(fingerprint$3 near10(read$3 or detect$4 or scan$4))same(discharg$3 or bleed$3 or ground$3 or remov$6) same(cover$3 or door$2 or switch$3 or knob$2 or key$1 or button$4 or hand$3)	US-PGPUB; USPAT	OR	ON	2006/06/07 14:23
L2	1025	(fingerprint$3 near10(read$3 or detect$4 or scan$4 captur$4))same(discharg$3 or bleed$3 or ground$3 or remov$6)	US-PGPUB; USPAT	OR	ON	2006/06/07 14:22
L3	205	2 same(electro$6 or static$3 or ESD$2 or EMI$2)	US-PGPUB; USPAT	OR	ON	2006/06/07 14:22
L4	37	3 same(finger$3 or preson$3 or user$3 or operator$2 or viewer$3) near10(access$3 or open$4 or touch$3 or push$3)	US-PGPUB; USPAT	OR	ON	2006/06/07 14:28
L5	1789	(fingerprint$3)same(read$3 or detect$4 or scan$4 captur$4)same(discharg$3 or bleed$3 or ground$3 or remov$6)	US-PGPUB; USPAT	OR	ON	2006/06/07 14:22
L6	319	5 same(electro$6 or static$3 or ESD$2 or EMI$2)	US-PGPUB; USPAT	OR	ON	2006/06/07 14:22
L7	46	6 same(finger$3 or preson$3 or user$3 or operator$2 or viewer$3) near10(access$3 or open$4 or touch$3 or push$3)	US-PGPUB; USPAT	OR	ON	2006/06/07 14:24
L8	114	6 same(cover$3 or door$2 or switch$3 or knob$2 or key$1 or button$4 or hand$3)	US-PGPUB; USPAT	OR	ON	2006/06/07 14:23
L9	23	8 same(finger$3 or preson$3 or user$3 or operator$2 or viewer$3) near10(access$3 or open$4 or touch$3 or push$3)	US-PGPUB; USPAT	OR	ON	2006/06/07 14:24
L10	1	"6278887".PN.	USPAT; USOCR	OR	ON	2006/06/07 14:26
L11	1	"6181254".PN.	USPAT; USOCR	OR	ON	2006/06/07 14:27
L12	1	"6164403".PN.	USPAT; USOCR	OR	ON	2006/06/07 14:27
L13	1	"6164540".PN.	USPAT; USOCR	OR	ON	2006/06/07 14:29
L14	1	"5978495".PN.	USPAT; USOCR	OR	ON	2006/06/07 14:29

L15	1	"6164540".PN.	USPAT; USOCR	OR	ON	2006/06/07 14:49
L16	1	"5978495".PN.	USPAT; USOCR	OR	ON	2006/06/07 14:50
L17	1	"6164540".PN.	USPAT; USOCR	OR	ON	2006/06/07 15:16
L18	1	"6002786".PN.	USPAT; USOCR	OR	ON	2006/06/07 15:20

IEEE Xplore

Search Result - Print Format

Key: IEEE JNL = IEEE Journal or Magazine, IEE JNL = IEE Journal or Magazine, IEEE CNF = IEEE Conference, I
CNF = IEE Conference, IEEE STD = IEEE Standard

1. **Enhancing partial discharge measurement with extended resolution analyser**
   Senthil Kumar, S.; Narayanachar, M.N.; Nema, R.S.;
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3. **Experimental and simulation study of spherically convergent beam fusion**
   Takeuchi, Y.; Yamauchi, K.; Ogino, Y.; Watanabe, M.; Okino, A.; Kwang-Cheol Ko; Hotta, E.;
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